

Docket No. 262790US6YA PCT
IN RE APPLICATION OF: Eric J STRANG, et al.
SERIAL NO: 10/521,118
FILED: January 12, 2005
FOR: METHOD AND SYSTEM FOR ELECTRON DENSITY MEASUREMENT



RESPONSE UNDER 37 CFR 1.116-
EXPEDITED PROCEDURE EXAMINING
GROUP 2857

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:
Transmitted herewith is an amendment in the above-identified application.

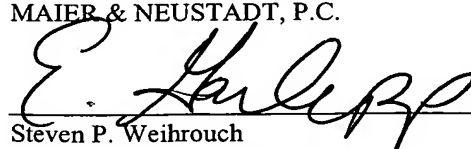
- ☒ No additional fee is required
☐ Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.
☐ Additional documents filed herewith:

The Fee has been calculated as shown below:

CLAIMS	CLAIMS REMAINING		HIGHEST NUMBER PREVIOUSLY PAID	NO. EXTRA CLAIMS	RATE	CALCULATIONS
TOTAL	42	MINUS	42	0	x \$50 =	\$0.00
INDEPENDENT	6	MINUS	6	0	x \$200 =	\$0.00
APPLICATION SIZE		MINUS	100	0 (each addtl. 50 sheets)	x \$250 =	\$0.00
		<input type="checkbox"/> MULTIPLE DEPENDENT CLAIMS			+ \$360 =	\$0.00
		TOTAL OF ABOVE CALCULATIONS				\$0.00
		<input type="checkbox"/> Reduction by 50% for filing by Small Entity				\$0.00
		TOTAL				\$0.00

- ☐ A check in the amount of \$0.00 is attached.
☐ Credit card payment form is attached to cover the fees in the amount of \$0.00
☒ Please charge any additional Fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
☒ If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

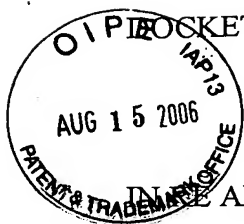

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POCKET NO: 262790US6YA PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN APPLICATION OF :

ERIC J STRANG, ET AL. :

EXAMINER: BARBEE, MANUEL L

SERIAL NO: 10/521,118 :

FILED: JANUARY 12, 2005 :

GROUP ART UNIT: 2857

FOR: METHOD AND SYSTEM FOR
ELECTRON DENSITY MEASUREMENT :

AMENDMENT

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Responsive to the Office Action mailed June 15, 2006, please amend the above-identified patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 12 of this paper.